



EMI TEST REPORT

Test Report No. : 30CE0150-HO-B

Applicant : Sharp Corporation, Communication Systems Group.
Type of Equipment : Cellular Phone
Model No. : SH-05B
FCC ID : APYHRO00116
Test regulation : FCC Part 15 Subpart B 2009 Class B
Test Result : Complied

1. This test report shall not be reproduced in full or partial, without the written approval of UL Japan, Inc.
2. The results in this report apply only to the sample tested.
3. This sample tested is in compliance with the above regulation.
4. The test results in this report are traceable to the national or international standards.
5. This test report must not be used by the customer product certification, approval, or endorsement by NVLAP, NIST, or any agency of the Federal Government.

Date of test:

December 2, 2009

Tested by:

Motoya Imura
EMC Services

Approved by :

Shinya Watanabe
Group Leader of EMC Services



NVLAP LAB CODE: 200572-0

This laboratory is accredited by the NVLAP LAB CODE 200572-0, U.S.A. The tests reported herein have been performed in accordance with its terms of accreditation.

*As for the range of Accreditation in NVLAP, you may refer to the WEB address,

<http://uljapan.co.jp/emc/nvlap.html>

UL Japan, Inc.

Head Office EMC Lab.

4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN

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SECTION 1: Customer information

Company Name : Sharp Corporation, Communication Systems Group.
Brand Name : SHARP
Address : 2-13-1 Iida Hachihonmatsu HigashiHiroshima-City, Hiroshima,739-0192, Japan
Telephone Number : +81-82-420-1825
Facsimile Number : +81-82-420-1829
Contact Person : Kazuo Sugimoto

SECTION 2: Equipment under test (E.U.T.)

2.1 Identification of E.U.T.

Type of Equipment : Cellular Phone
Model No. : SH-05B
Serial No. : Refer to Section 4, Clause 4.2
Receipt Date of Sample : December 2, 2009
Country of Mass-production : Japan
Condition of EUT : Production prototype
(Not for Sale: This sample is equivalent to mass-produced items.)
Modification of EUT : No Modification by the test lab

2.2 Product Description

Model No: SH-05B (referred to as the EUT in this report) is the Cellular Phone.

Feature of EUT: WCDMA Cellular Phone / Felica enable
-WCDMA: (EU: 2000M, USA: 850, JPN: 800/2000)

Clock frequency(ies) in the system: 48MHz (Oscillator), 500.5MHz (CPU clock)

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SECTION 3: Test specification, procedures & results

3.1 Test specification

Test Specification : FCC Part 15 Subpart B 2009, final revised on December 2, 2009
Title : FCC 47CFR Part15 Radio Frequency Device
Subpart B Unintentional Radiators

* The revision on December 2, 2009 does not influence the test specification applied to the EUT.

3.2 Procedures and results

Item	Test Procedure	Limits	Deviation	Worst margin	Result
Conducted emission	FCC: ANSI C63.4: 2003 7. AC powerline conducted emission measurements	Class B	N/A	[QP] 11.7dB 3.77310MHz, L, USB Data Com mode [AV] 13.6dB 2.03205MHz, N, 2.03242MHz, L, USB Data Com mode	Complied
Radiated emission	FCC: ANSI C63.4: 2003 8. Radiated emission measurements	Class B	N/A	6.3dB 750.000MHz, Horizontal, USB Data Com mode	Complied

*Note: UL Japan, Inc's EMI Work Procedure QPM05.

3.3 Addition to standard

No addition, exclusion nor deviation has been made from the standard.

3.4 Uncertainty

EMI

The following uncertainties have been calculated to provide a confidence level of 95% using a coverage factor k=2.

Test room (semi-anechoic chamber)	Conducted emission (+dB)
	150kHz-30MHz
No.1	2.6dB
No.2	2.9dB
No.3	3.3dB
No.4	2.8dB

Test room (semi-anechoic chamber)	Radiated emission (10m*)(±dB)			Radiated emission					
				(3m*)(±dB)					(1m*)(±dB)
	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	9kHz -30MHz	30MHz -300MHz	300MHz -1GHz	1GHz -18GHz	18GHz -26.5GHz	26.5GHz -40GHz
No.1	2.7dB	4.8dB	5.0dB	2.9dB	4.8dB	5.0dB	3.9dB	4.5dB	4.4dB
No.2	-	-	-	3.5dB	4.8dB	5.1dB	4.0dB	4.3dB	4.2dB
No.3	-	-	-	3.8dB	4.6dB	4.7dB	4.0dB	4.5dB	4.4dB
No.4	-	-	-	3.5dB	4.4dB	4.9dB	4.0dB	4.6dB	4.5dB

*10m/3m/1m = Measurement distance

Conducted Emission test

The data listed in this test report has enough margin, more than the site margin.

Radiated emission test(3m)

The data listed in this test report has enough margin, more than the site margin.

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3.5 Test Location

UL Japan, Inc. Head Office EMC Lab. *NVLAP Lab. code: 200572-0
4383-326 Asama-cho, Ise-shi, Mie-ken 516-0021 JAPAN
Telephone : +81 596 24 8116 Facsimile : +81 596 24 8124

	FCC Registration Number	IC Registration Number	Width x Depth x Height (m)	Size of reference ground plane (m) / horizontal conducting plane	Other rooms
No.1 semi-anechoic chamber	313583	2973C-1	19.2 x 11.2 x 7.7m	7.0 x 6.0m	No.1 Power source room
No.2 semi-anechoic chamber	655103	2973C-2	7.5 x 5.8 x 5.2m	4.0 x 4.0m	-
No.3 semi-anechoic chamber	148738	2973C-3	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.3 Preparation room
No.3 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.4 semi-anechoic chamber	134570	2973C-4	12.0 x 8.5 x 5.9m	6.8 x 5.75m	No.4 Preparation room
No.4 shielded room	-	-	4.0 x 6.0 x 2.7m	N/A	-
No.5 semi-anechoic chamber	-	-	6.0 x 6.0 x 3.9m	6.0 x 6.0m	-
No.6 shielded room	-	-	4.0 x 4.5 x 2.7m	4.75 x 5.4 m	-
No.6 measurement room	-	-	4.75 x 5.4 x 3.0m	4.75 x 4.15 m	-
No.7 shielded room	-	-	4.7 x 7.5 x 2.7m	4.7 x 7.5m	-
No.8 measurement room	-	-	3.1 x 5.0 x 2.7m	N/A	-
No.9 measurement room	-	-	8.0 x 4.5 x 2.8m	2.0 x 2.0m	-
No.10 measurement room	-	-	2.6 x 2.8 x 2.5m	2.4 x 2.4m	-
No.11 measurement room	-	-	3.1 x 3.4 x 3.0m	2.4 x 3.4m	-

* Size of vertical conducting plane (for Conducted Emission test) : 2.0 x 2.0m for No.1, No.2, No.3, and No.4 semi-anechoic chambers and No.3 and No.4 shielded rooms.

3.6 Test set up, Data of EMI, and Test instruments

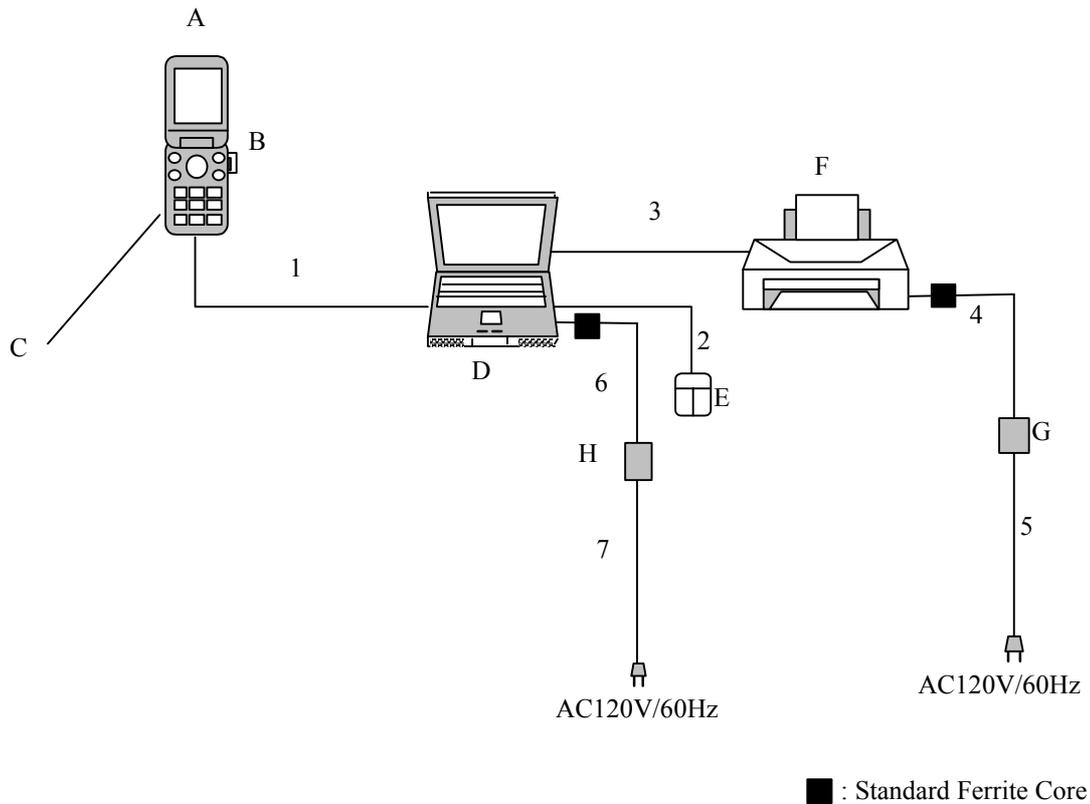
Refer to APPENDIX 1 to 3.

SECTION 4: Operation of E.U.T. during testing

4.1 Operating modes

The mode(s) : 1) USB Data Com mode
The USB data is communicated between EUT and Personal computer (Pair of EUT).
2) Standby mode
Standby state for USB communication

4.2 Configuration and peripherals



*Cabling and setup were taken into consideration and test data was taken under worse case conditions.

Description of EUT and Support equipment

No.	Item	Model number	Serial number	Manufacturer	Remark
A	Cellular Phone	SH-05B	004401112235268	SHARP	EUT
B	micro SD Memory Card	SD-08G	0852K93900Y	TOSHIBA	EUT
C	Lithium-Ion Battery	SH21	None	SHARP	EUT
D	Personal Computer	PP11L	0D4571-48643 58P-1053	Dell	-
E	Mouse	MOC5UO	H0S03VBY	Dell	-
F	Printer	895Cxi	SG8BA1W18J	Hewlett-Packard	-
G	AC Adapter (Printer)	C4557-60004	C8L01B	Hewlett Packard	-
H	AC Adapter (PC)	PA-1650-05D2	0F70-71615-77H-0D63	Dell	-

List of cables used

No.	Name	Length (m)	Shield	
			Cable	Connector
1	USB Data Cable	0.75	Shielded	Shielded
2	Mouse Cable	1.85	Shielded	Shielded
3	Parallel Printer Cable	2.00	Shielded	Shielded
4	DC Cable (Printer)	2.00	Unshielded	Unshielded
5	AC Cable (Printer)	1.75	Unshielded	Unshielded
6	DC Cable (PC)	1.85	Unshielded	Unshielded
7	AC Cable (PC)	0.90	Unshielded	Unshielded

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SECTION 5: Conducted Emission

5.1 Operating environment

Test place : No.1 semi anechoic chamber
Temperature : See data
Humidity : See data

5.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The rear of tabletop was located 40cm to the vertical conducting plane. The rear of EUT and its peripherals was aligned and flushed with rear of tabletop. All other surfaces of tabletop were at least 80cm from any other grounded conducting surface. EUT was located 80cm from the LISN/AMN and excess AC cable was bundled in center. I/O cables that were connected to the other peripherals were bundled in center. They were folded back and forth forming a bundle 30cm to 40cm long and were hanged at a 40cm height to the ground plane. Each EUT current-carrying power lead, except the ground (safety) lead, was individually connected through a LISN/AMN to the input power source. All unused 50 ohm connectors of the LISN/AMN were resistivity terminated in 50 ohm when not connected to the measuring equipment. Photographs of the set up are shown in Appendix 1.

Frequency range : 0.15 MHz-30MHz
EUT position : Table top
EUT operation mode : See Clause 4.1

5.3 Test procedure

The AC Mains Terminal Continuous disturbance Voltage has been measured with the EUT within a semi anechoic chamber. The EUT was connected to a Line Impedance Stabilization Network (LISN)/ Artificial Mains network (AMN). An overview sweep with peak detection has been performed. The measurements have been performed with a quasi-peak detector and if required, with an average detector.

The conducted emission measurements were made with the following detector function of the test receiver.

Detector Type : Quasi-Peak and Average
IF Bandwidth : 9 kHz

5.4 Test result

Summary of the test results: Pass

Date: December 2, 2009

Test engineer: Motoya Imura

UL Japan, Inc.

Head Office EMC Lab.

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SECTION 6: Radiated Emission

6.1 Operating environment

Test place : No.1 semi anechoic chamber
Temperature : See data
Humidity : See data

6.2 Test configuration

EUT was placed on a urethane platform of nominal size, 1.0m by 1.5m, raised 0.8m above the conducting ground plane. The EUT was set on the edge of the tabletop. Test was made with the antenna positioned in both the horizontal and vertical planes of polarization. The measurement antenna was varied in height above the conducting ground plane to obtain the maximum signal strength. Photographs of the set up are shown in Appendix 1.

6.3 Test conditions

Frequency range : 30MHz-300MHz (Biconical antenna) / 300MHz-1000MHz (Logperiodic antenna)
1000MHz -5000MHz (Horn antenna)
Test distance : 3m
EUT position : Table top
EUT operation mode : See Clause 4.1

6.4 Test procedure

The height of the measuring antenna varied between 1 and 4m and EUT was rotated a full revolution in order to obtain the maximum value of the electric field intensity. The measurements were performed for both vertical and horizontal antenna polarization with the Test Receiver, or the Spectrum Analyzer. The radiated emission measurements were made with the following detector function of the test receiver and the Spectrum analyzer.

Frequency	Below 1GHz	Above 1GHz
Instrument used	Test Receiver	Spectrum Analyzer
IF Bandwidth	QP: BW 120kHz	PK: RBW:1MHz/VBW: 1MHz AV *1): RBW:1MHz/VBW:10Hz

*1) When using Spectrum analyzer, the test was made with adjusting span to zero by using peak hold.

- The carrier level and noise levels were confirmed at each position of X, Y and Z axes of EUT and/or GPS antenna to see the position of maximum noise, and the test was made at the position that has the maximum noise.

6.5 Test result

Summary of the test results: Pass

Date: December 2, 2009

Test engineer: Motoya Imura

APPENDIX 1: Photographs of test setup

Conducted Emission

This page has been submitted for a separate exhibit.

Radiated Emission

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Worst Case Position (Horizontal: X-axis/ Vertical:X-axis)

This page has been submitted for a separate exhibit.

APPENDIX 2: Data of EMI test

**Conducted Emission
USB Data Com mode**

DATA OF CONDUCTED EMISSION TEST

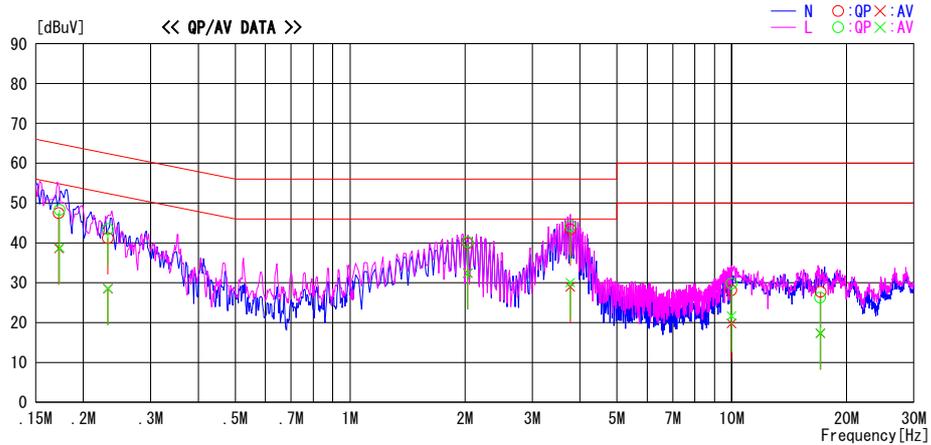
UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2009/12/02

Company : Sharp Corporation
Kind of EUT : Cellular Phone
Model No. : SH-05B
Serial No. : 00440112235268

Report No. : 30CE0150-HO
Power : AC 120V / 60Hz
Temp./Humi. : 22deg. C / 38%
Engineer : Motoya Imura

Mode / Remarks : USB Data Com Mode

LIMIT : FCC15.107(a) QP
FCC15.107(a) AV



Frequency [MHz]	Reading Level		Corr. Factor [dB]	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.17235	47.3	38.4	0.2	47.5	38.6	64.8	54.8	17.3	16.2	N	
0.23187	40.9	28.2	0.3	41.2	28.5	62.4	52.4	21.2	23.9	N	
2.03205	39.4	31.9	0.5	39.9	32.4	56.0	46.0	16.1	13.6	N	
3.77329	42.6	28.2	0.8	43.4	29.0	56.0	46.0	12.6	17.0	N	
9.98235	26.7	18.4	1.4	28.1	19.8	60.0	50.0	31.9	30.2	N	
17.06711	25.6	15.2	2.1	27.7	17.3	60.0	50.0	32.3	32.7	N	
0.17326	48.1	38.6	0.2	48.3	38.8	64.8	54.8	16.5	16.0	L	
0.23165	43.2	28.3	0.3	43.5	28.6	62.4	52.4	18.9	23.8	L	
2.03242	39.7	31.9	0.5	40.2	32.4	56.0	46.0	15.8	13.6	L	
3.77310	43.5	29.3	0.8	44.3	30.1	56.0	46.0	11.7	15.9	L	
9.98357	28.5	20.3	1.4	29.9	21.7	60.0	50.0	30.2	28.3	L	
17.06560	24.2	15.2	2.1	26.3	17.3	60.0	50.0	33.7	32.7	L	

CHART: WITH FACTOR, Peak hold data. CALCULATION: RESULT[dBuV]=READING[dBuV]+C. F[dB] (LISN LOSS+CABLE LOSS)
Except for the above table : adequate margin data below the limits.

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Conducted Emission Standby mode

DATA OF CONDUCTED EMISSION TEST

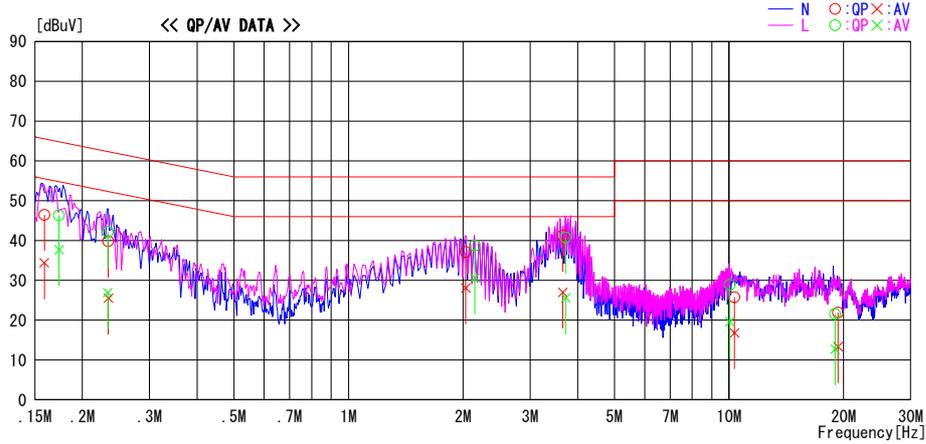
UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2009/12/02

Company : Sharp Corporation
Kind of EUT : Cellular Phone
Model No. : SH-05B
Serial No. : 004401112235268

Report No. : 30CE0150-HO
Power : AC 120V / 60Hz
Temp./Humi. : 22deg. C / 38%
Engineer : Motoya Imura

Mode / Remarks : Standby Mode

LIMIT : FCC15.107(a) QP
FCC15.107(a) AV



Frequency [MHz]	Reading Level		Corr. Factor [dB]	Results		Limit		Margin		Phase	Comment
	QP [dBuV]	AV [dBuV]		QP [dBuV]	AV [dBuV]	QP [dBuV]	AV [dBuV]	QP [dB]	AV [dB]		
0.15875	46.3	34.2	0.2	46.5	34.4	65.5	55.5	19.0	21.1	N	
0.23390	39.5	25.2	0.3	39.8	25.5	62.3	52.3	22.5	26.8	N	
2.03240	36.6	27.6	0.5	37.1	28.1	56.0	46.0	18.9	17.9	N	
3.65720	40.5	26.2	0.8	41.3	27.0	56.0	46.0	14.7	19.0	N	
10.33679	24.2	15.3	1.5	25.7	16.8	60.0	50.0	34.3	33.2	N	
19.34560	19.6	11.0	2.3	21.9	13.3	60.0	50.0	38.1	36.7	N	
0.17354	46.2	37.5	0.2	46.4	37.7	64.8	54.8	18.4	17.1	L	
0.23315	41.8	26.6	0.3	42.1	26.9	62.3	52.3	20.2	25.4	L	
2.14890	38.1	30.0	0.6	38.7	30.6	56.0	46.0	17.3	15.4	L	
3.72002	39.9	24.8	0.8	40.7	25.6	56.0	46.0	15.3	20.4	L	
10.04620	27.3	18.1	1.5	28.8	19.6	60.0	50.0	31.2	30.4	L	
18.99725	19.3	10.4	2.3	21.6	12.7	60.0	50.0	38.4	37.3	L	

CHART: WITH FACTOR, Peak hold data. CALCULATION: RESULT [dBuV] = READING [dBuV] + C. F [dB] (LISN LOSS + CABLE LOSS)
Except for the above table : adequate margin data below the limits.

*The limit is rounded down to one decimal place.

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission
(below 1GHz)
USB Data Com mode

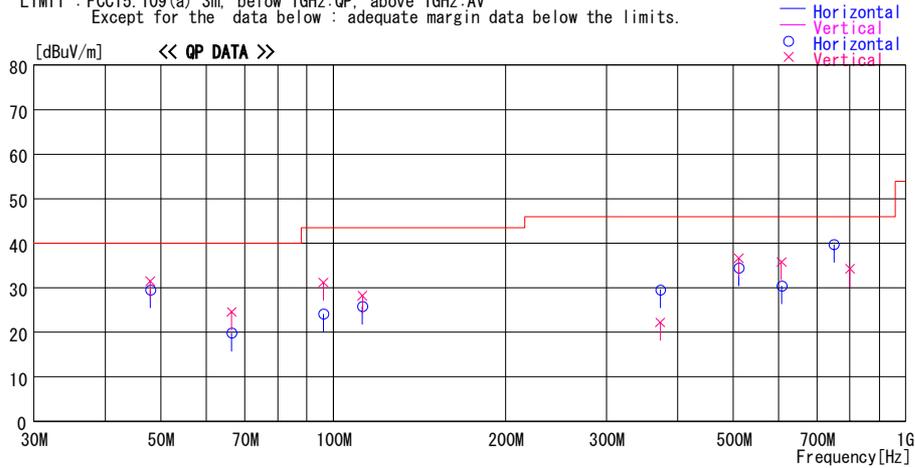
DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2009/12/02

Company : Sharp Corporation
Kind of EUT : Cellular Phone
Model No. : SH-05B
Serial No. : 004401112235268
Report No. : 30CE0150-HO
Power : AC 120V / 60Hz
Temp./Humi. : 22deg. C / 38%
Engineer : Motoya Imura

Mode / Remarks: USB Data Com Mode Worst Axis(Hor:X, Ver:X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV
Except for the data below : adequate margin data below the limits.



Frequency [MHz]	Reading [dBuV]	DET	Antenna		Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Loss & Gain [dB]							
47.925	52.0	QP	11.6	-34.1	29.5	91	271	Hori.	40.0	10.5	
47.917	54.0	QP	11.6	-34.1	31.5	72	100	Vert.	40.0	8.5	
66.531	46.6	QP	7.0	-33.8	19.8	357	355	Hori.	40.0	20.2	
66.527	51.3	QP	7.0	-33.8	24.5	103	100	Vert.	40.0	15.5	
96.137	47.9	QP	9.3	-33.1	24.1	254	307	Hori.	43.5	19.4	
96.136	55.0	QP	9.3	-33.1	31.2	130	100	Vert.	43.5	12.3	
112.495	46.7	QP	11.9	-32.8	25.8	302	339	Hori.	43.5	17.7	
112.621	49.1	QP	11.9	-32.8	28.2	128	100	Vert.	43.5	15.3	
372.944	44.3	QP	15.3	-30.1	29.5	239	113	Hori.	46.0	16.5	
372.946	37.0	QP	15.3	-30.1	22.2	69	100	Vert.	46.0	23.8	
511.289	45.3	QP	18.4	-29.3	34.4	143	100	Hori.	46.0	11.6	
511.311	47.5	QP	18.4	-29.3	36.6	23	128	Vert.	46.0	9.4	
607.167	45.5	QP	19.0	-28.7	35.8	335	100	Vert.	46.0	10.2	
607.770	40.0	QP	19.1	-28.7	30.4	24	308	Hori.	46.0	15.6	
750.000	46.3	QP	21.2	-27.8	39.7	74	127	Hori.	46.0	6.3	
800.006	39.6	QP	22.0	-27.4	34.2	88	122	Vert.	46.0	11.8	

CHART: WITH FACTOR ANT TYPE: -30MHz: LOOP, 30-300MHz: BICONICAL, 300MHz-1000MHz: LOGPERIODIC, 1000MHz-: HORN
CALCULATION: RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission
(below 1GHz)
Standby mode

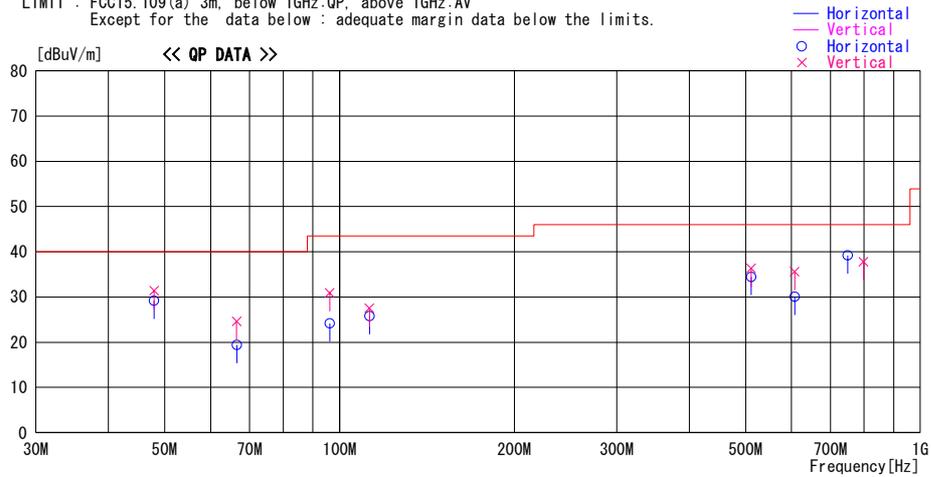
DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2009/12/02

Company : Sharp Corporation
Kind of EUT : Cellular Phone
Model No. : SH-05B
Serial No. : 00440112235268
Report No. : 30CE0150-HO
Power : AC 120V / 60Hz
Temp./Humi. : 22deg. C / 38%
Engineer : Motoya Imura

Mode / Remarks : Standby Mode Worst Axis(Hor:X, Ver:X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV
Except for the data below : adequate margin data below the limits.



Frequency [MHz]	Reading [dBuV]	DET	Antenna		Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Loss& Gain [dB]							
47.908	51.7	QP	11.6	-34.1	29.2	94	302	Hori.	40.0	10.8	
47.943	54.0	QP	11.5	-34.1	31.4	77	100	Vert.	40.0	8.6	
66.498	51.4	QP	7.0	-33.8	24.6	88	102	Vert.	40.0	15.4	
66.534	46.2	QP	7.0	-33.8	19.4	359	361	Hori.	40.0	20.6	
96.143	48.0	QP	9.3	-33.1	24.2	253	331	Hori.	43.5	19.3	
96.157	54.7	QP	9.3	-33.1	30.9	128	100	Vert.	43.5	12.6	
112.621	46.7	QP	11.9	-32.8	25.8	307	372	Hori.	43.5	17.7	
112.621	48.4	QP	11.9	-32.8	27.5	117	100	Vert.	43.5	16.0	
511.305	45.3	QP	18.4	-29.3	34.4	149	100	Hori.	46.0	11.6	
511.306	47.2	QP	18.4	-29.3	36.3	26	119	Vert.	46.0	9.7	
607.204	45.3	QP	19.0	-28.7	35.6	343	100	Vert.	46.0	10.4	
607.322	39.8	QP	19.0	-28.7	30.1	44	310	Hori.	46.0	15.9	
750.016	45.8	QP	21.2	-27.8	39.2	80	124	Hori.	46.0	6.8	
797.940	43.3	QP	21.9	-27.4	37.8	72	169	Vert.	46.0	8.2	

CHART: WITH FACTOR ANT TYPE: -30MHz: LOOP, 30-300MHz: BICONICAL, 300MHz-1000MHz: LOGPERIODIC, 1000MHz-: HORN
CALCULATION: RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission
(Above 1GHz)
USB Data Com mode

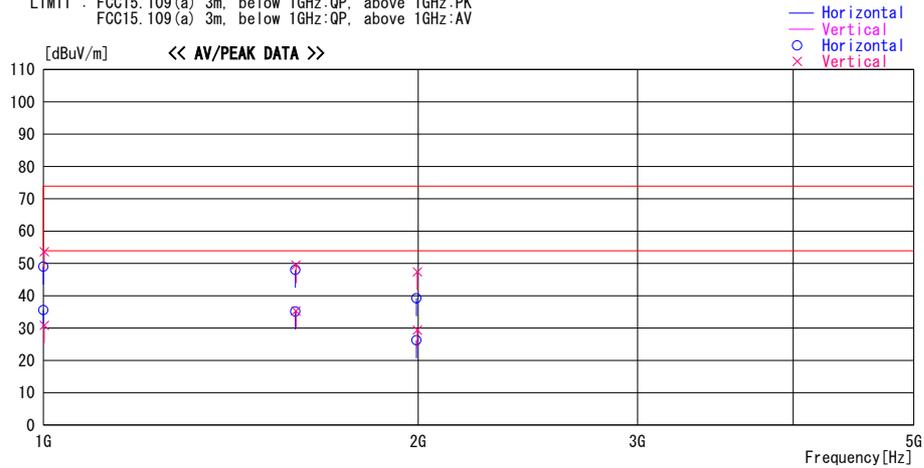
DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2009/12/02

Company : Sharp Corporation Report No. : 30CE0150-HO
Kind of EUT : Cellular Phone Power : AC 120V / 60Hz
Model No. : SH-05B Temp./Humi. : 22deg.C / 38%
Serial No. : 00440112235268 Engineer : Motoya Imura

Mode / Remarks : USB Data Com Mode Worst Axis(Hor:X, Ver:X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Gain [dB]							
1000.002	59.3	PK	24.9	-35.2	49.0	12	100	Hori.	73.9	24.9	
1000.002	45.9	AV	24.9	-35.2	35.6	12	100	Hori.	53.9	18.3	
1001.358	41.2	AV	24.9	-35.2	30.9	45	100	Vert.	53.9	23.0	
1001.358	63.9	PK	24.9	-35.2	53.6	45	100	Vert.	73.9	20.3	
1593.352	56.3	PK	26.3	-34.6	48.0	340	120	Hori.	73.9	25.9	
1593.352	43.4	AV	26.3	-34.6	35.1	340	120	Hori.	53.9	18.8	
1594.997	57.8	PK	26.3	-34.6	49.5	330	120	Vert.	73.9	24.4	
1594.997	43.6	AV	26.3	-34.6	35.3	330	120	Vert.	53.9	18.6	
1993.441	48.0	PK	25.6	-34.4	39.2	76	108	Hori.	73.9	34.7	
1993.441	35.0	AV	25.6	-34.4	26.2	76	108	Hori.	53.9	27.7	
1996.330	38.2	AV	25.6	-34.4	29.4	103	100	Vert.	53.9	24.5	
1996.330	56.2	PK	25.6	-34.4	47.4	103	100	Vert.	73.9	26.5	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz--:HORN
CALCULATION:RESULT = READING + ANT FACTOR + LOSS (CABLE+ATTEN.) - GAIN (AMP)

*The test result is rounded off to one or two decimal places, so some differences might be observed.

Radiated Emission
(Above 1GHz)
Standby mode

DATA OF RADIATED EMISSION TEST

UL Japan, Inc. Head Office EMC Lab. No.1 Semi Anechoic Chamber
Date : 2009/12/02

Company : Sharp Corporation
Kind of EUT : Cellular Phone
Model No. : SH-05B
Serial No. : 004401112235268
Report No. : 30CE0150-H0
Power : AC 120V / 60Hz
Temp./Humi. : 22deg. C / 38%
Engineer : Motoya Imura

Mode / Remarks : Standby Mode Worst Axis(Hor:X, Ver:X)

LIMIT : FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:PK
FCC15.109(a) 3m, below 1GHz:QP, above 1GHz:AV



Frequency [MHz]	Reading [dBuV]	DET	Antenna	Loss&	Level [dBuV/m]	Angle [Deg]	Height [cm]	Polar.	Limit [dBuV/m]	Margin [dB]	Comment
			Factor [dB/m]	Gain [dB]							
1593.330	57.9	PK	26.3	-34.6	49.6	332	122	Vert.	73.9	24.3	
1593.330	43.8	AV	26.3	-34.6	35.5	332	122	Vert.	53.9	18.5	
1595.367	52.2	PK	26.3	-34.6	43.9	332	122	Hori.	73.9	30.0	
1595.367	37.6	AV	26.3	-34.6	29.3	332	122	Hori.	53.9	24.6	
1993.328	48.1	PK	25.6	-34.4	39.3	76	100	Hori.	73.9	34.6	
1993.328	34.9	AV	25.6	-34.4	26.1	76	100	Hori.	53.9	27.8	
1993.333	38.2	AV	25.6	-34.4	29.4	98	100	Vert.	53.9	24.5	
1993.333	56.5	PK	25.6	-34.4	47.7	98	100	Vert.	73.9	26.2	

CHART:WITH FACTOR ANT TYPE: -30MHz:LOOP, 30-300MHz:BICONICAL, 300MHz-1000MHz:LOGPERIODIC, 1000MHz--:HORN
CALCULATION:RESULT = READING + ANT FACTOR + LOSS(CABLE+ATTEN.) - GAIN(AMP)

*The test result is rounded off to one or two decimal places, so some differences might be observed.

APPENDIX 3: Test instruments

EMI test equipment

Control No.	Instrument	Manufacturer	Model No	Serial No	Test Item	Calibration Date * Interval(month)
MAEC-01	Semi Anechoic Chamber(NSA)	TDK	Semi Anechoic Chamber 10m	DA-06881	RE/CE	2009/06/26 * 12
MOS-01	Digital Humidity Indicator	N.T	NT-1800	MOS01	RE/CE	2009/02/06 * 12
MJM-01	Measure	KDS	ES19-55	-	RE/CE	-
COTS-MEMI	EMI measurement program	TSJ	TEPTO-DV	-	RE/CE	-
MTR-01	Test Receiver	Rohde & Schwarz	ES140	100084	RE/CE	2008/12/01 * 12
MBA-01	Biconical Antenna	Schwarzbeck	BBA9106	VHA91032007	RE	2009/10/03 * 12
MLA-09	Logperiodic Antenna	Schwarzbeck	USLP9143B	9143B006	RE	2009/10/03 * 12
MAT-06	Attenuator(6dB)	Weinschel Corp	2	BL1069	RE	2009/11/26 * 12
MCC-01	Coaxial Cable 0.1-3000MHz	Suhner/storm/Agilent /TSJ	-	-	RE	2009/10/09 * 12
MPA-20	Pre Amplifier	Elena	EPA-4020YA	030801	RE	2009/03/17 * 12
MHA-05	Horn Antenna 1-18GHz	Schwarzbeck	BBHA9120D	253	RE	2009/06/15 * 12
MCC-18	Microwave Cable 1G-26.5GHz	Suhner	SUCOFLEX 104	233010(1m) / 292410(5m)	RE	2009/09/16 * 12
MPA-01	Pre Amplifier	Agilent	8449B	3008A01671	RE	2009/02/12 * 12
MSA-04	Spectrum Analyzer	Agilent	E4448A	US44300523	RE	2009/08/25 * 12
MLS-02	LISN(AMN)	Schwarzbeck	NSLK8127	8127383	CE(EUT)	2009/06/22 * 12
MLS-03	LISN(AMN)	Schwarzbeck	NSLK8127	8127384	CE(AE)	2009/07/16 * 12
MTA-06	Terminator	MCL	BTRM-50	1 9951	CE	2009/02/17 * 12
MCC-03	Coaxial Cable	Fujikura/Suhner/TSJ	5D-2W(20m)/3D-2W(7.5m)/RG400u(1.5m)/RFM-E421(Switcher)	-/01068(Switcher)	CE	2008/12/16 * 12

The expiration date of the calibration is the end of the expired month.

All equipment is calibrated with traceable calibrations. Each calibration is traceable to the national or international standards. As for some calibrations performed after the tested dates, those test equipment have been controlled by means of an unbroken chains of calibrations.

Test Item:

- CE: Conducted emission
- RE: Radiated emission

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